

Notice of References Cited	Application/Control No. 10/511,785		Applicant(s)/Patent Under Reexamination LEFEVRE ET AL.	
	Examiner CHRISTINE CHEN		Art Unit 4116	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0104589 A1	08-2002	Van den Sype et al.	148/233
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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